Notice of References Cited Application/Control No. 10/605,489 Examiner Chau N Nguyen Applicant(s)/Patent Under Reexamination LEE ET AL. Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	Α	US-6,329,602	12-2001	Ushiyama et al.	· 174/137R
	В	US-4,909,638	03-1990	Muto, Takashi	384/273
	С	US-5,962,945	10-1999	Krenzer et al.	310/208
	D	US-6,420,812	07-2002	Emery, Franklin T.	310/196
	E	US-4,415,223	11-1983	Asick, John C.	439/610
	F	US-4,490,422	12-1984	Pascher, Helmut	428/35.1
	G	US-5,873,144	02-1999	Tupper et al.	16/18CG
	Н	US-6,043,582	03-2000	Markovitz et al.	310/213
	I	US-3,050,787	08-1962	JASNIEWSKI JOSEPH M; et. al.	264/102
	J	US-			
	К	US-			
·	L	US-			
	М	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	z	JP2-17841	01-1990	Japan	Haga et al.	
	0	JP56-29435	03-1981	Japan	Osono et al.	
	Р					. "
	σ					
	R					
	S					
	Т					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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	W	
	x	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.